



FAST CMOS QUAD 2-INPUT MULTIPLEXER

IDT74FCT2257AT/CT

FEATURES:

- A and C grades
- Low input and output leakage $\leq 1\mu\text{A}$ (max.)
- CMOS power levels
- True TTL input and output compatibility:
 - $V_{OH} = 3.3\text{V}$ (typ.)
 - $V_{OL} = 0.3\text{V}$ (typ.)
- Meets or exceeds JEDEC standard 18 specifications
- Resistor outputs (-15mA I_{OH} , 12mA I_{OL})
- Reduced system switching noise
- Available in SOIC and QSOP packages

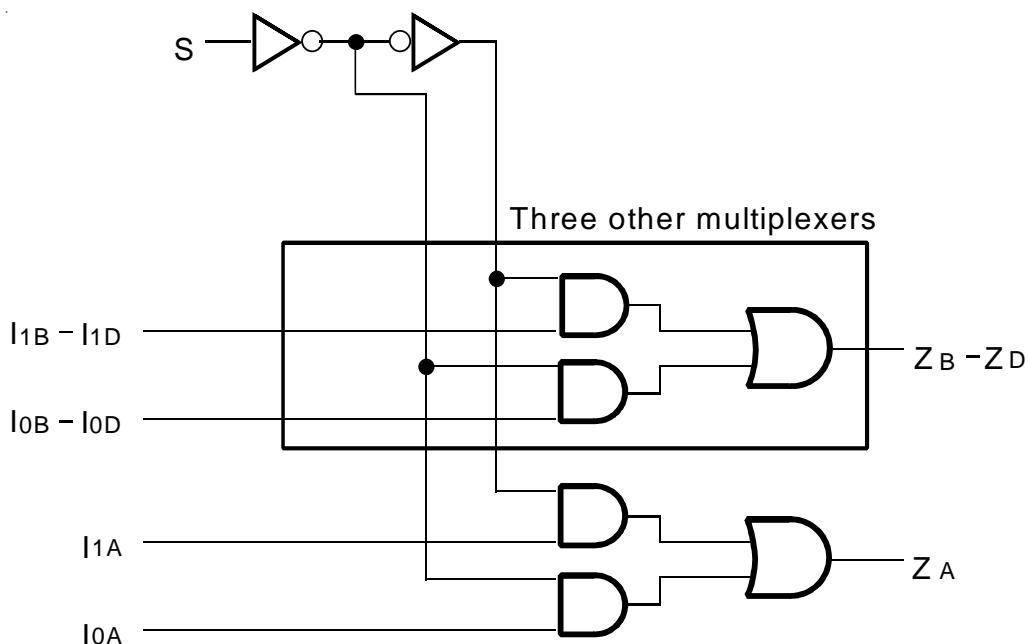
DESCRIPTION:

The FCT2257T is a high-speed quad 2-input multiplexer built using an advanced dual metal CMOS technology. Four bits of data from two sources can be selected using the common select input. The four buffered outputs present the selected data in the true (non-inverting) form.

The 2257T has a common Output Enable (\overline{OE}) input. When \overline{OE} is high, all outputs are switched to a high-impedance state allowing the outputs to interface directly with bus-oriented systems.

The FCT2257T has balanced output drive with current limiting resistors. This offers low ground bounce, minimal undershoot and controlled output fall times-reducing the need for external series terminating resistors. FCT2257T parts are plug-in replacements for FCT257T parts.

FUNCTIONAL BLOCK DIAGRAM

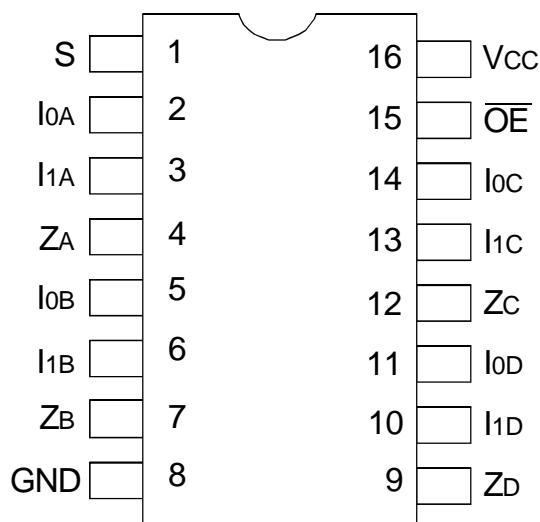


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INDUSTRIAL TEMPERATURE RANGE

JUNE 2002

PIN CONFIGURATION



SOIC/ QSOP
TOP VIEW

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Description	Max	Unit
VTERM ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to +7	V
VTERM ⁽³⁾	Terminal Voltage with Respect to GND	-0.5 to Vcc+0.5	V
TSTG	Storage Temperature	-65 to +150	°C
IOUT	DC Output Current	-60 to +120	mA

NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed Vcc by +0.5V unless otherwise noted.
- Inputs and Vcc terminals only.
- Output and I/O terminals only.

CAPACITANCE ($T_A = +25^\circ\text{C}$, $f = 1.0\text{MHz}$)

Symbol	Parameter ⁽¹⁾	Conditions	Typ.	Max.	Unit
CIN	Input Capacitance	$V_{IN} = 0\text{V}$	6	10	pF
COUT	Output Capacitance	$V_{OUT} = 0\text{V}$	8	12	pF

NOTE:

- This parameter is measured at characterization but not tested.

PIN DESCRIPTION

Pin Names	Description
I0A-I0D	Source 0 Data Inputs
I1A-I1D	Source 1 Data Inputs
OE	Output Enable (Active LOW)
S	Select Input
ZA-ZD	Outputs

FUNCTION TABLE⁽¹⁾

Inputs				Outputs
OE	S	I0	I1	
H	X	X	X	Z
L	H	X	L	L
L	H	X	H	H
L	L	L	X	L
L	L	H	X	H

NOTE:

- H = HIGH Voltage Level
L = LOW Voltage Level
X = Don't Care
Z = High-Impedance

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Industrial: TA = -40°C to +85°C, VCC = 5.0V ±5%

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
V _{IH}	Input HIGH Level	Guaranteed Logic HIGH Level		2	—	—	V
V _{IL}	Input LOW Level	Guaranteed Logic LOW Level		—	—	0.8	V
I _{IH}	Input HIGH Current ⁽⁴⁾	V _{CC} = Max.	V _I = 2.7V	—	—	±1	µA
I _{IL}	Input LOW Current ⁽⁴⁾	V _{CC} = Max.	V _I = 0.5V	—	—	±1	µA
I _{OZH}	High Impedance Output Current (3-State Output Pins) ⁽⁴⁾	V _{CC} = Max.	V _I = 2.7V	—	—	±1	µA
I _{OZL}			V _I = 0.5V	—	—	±1	
I _I	Input HIGH Current ⁽⁴⁾	V _{CC} = Max., V _I = V _{CC} (Max.)		—	—	±1	µA
V _{IK}	Clamp Diode Voltage	V _{CC} = Min., I _{IN} = -18mA		—	-0.7	-1.2	V
V _H	Input Hysteresis	—		—	200	—	mV
I _{QC}	Quiescent Power Supply Current	V _{CC} = Max. V _{IN} = GND or V _{CC}		—	0.01	1	µA

OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
I _{ODL}	Output LOW Current	V _{CC} = 5V, V _{IN} = V _{IH} or V _{IL} , V _{OUT} = 1.5V ⁽³⁾		16	48	—	mA
I _{ODH}	Output HIGH Current	V _{CC} = 5V, V _{IN} = V _{IH} or V _{IL} , V _{OUT} = 1.5V ⁽³⁾		-16	-48	—	mA
V _{OH}	Output HIGH Voltage	V _{CC} = Min V _{IN} = V _{IH} or V _{IL}	I _{OH} = -15mA	2.4	3.3	—	V
V _{OL}	Output LOW Voltage	V _{CC} = Min V _{IN} = V _{IH} or V _{IL}	I _{OL} = 12mA	—	0.3	0.5	V

NOTES:

- For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at V_{CC} = 5.0V, +25°C ambient.
- Not more than one output should be tested at one time. Duration of the test should not exceed one second.
- The test limit for this parameter is ±5µA at TA = -55°C.

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
ΔI_{CC}	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V^{(3)}$		—	0.5	2	mA
I_{CCD}	Dynamic Power Supply Current ⁽⁴⁾	$V_{CC} = \text{Max.}$ Outputs Open $\overline{OE} = \text{GND}$ One Input Toggling 50% Duty Cycle		—	0.06	0.12	mA/ MHz
I_C	Total Power Supply Current ⁽⁶⁾	$V_{CC} = \text{Max.}$ Outputs Open $f_O = 10\text{MHz}$ 50% Duty Cycle $\overline{OE} = \text{GND}$ One Bit Toggling	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	0.6	2.2	mA
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	0.9	3.2	
		$V_{CC} = \text{Max.}$ Outputs Open $f_O = 2.5\text{MHz}$ 50% Duty Cycle $\overline{OE} = \text{GND}$ Four Bits Toggling	$V_{IN} = V_{CC}$ $V_{IN} = \text{GND}$	—	0.6	2.2 ⁽⁵⁾	
			$V_{IN} = 3.4V$ $V_{IN} = \text{GND}$	—	1.6	6.2 ⁽⁵⁾	

NOTES:

1. For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical values are at $V_{CC} = 5.0V$, $+25^\circ\text{C}$ ambient.

3. Per TTL driven input ($V_{IN} = 3.4V$). All other inputs at V_{CC} or GND.

4. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.

5. Values for these conditions are examples of ΔI_{CC} formula. These limits are guaranteed but not tested.

$$I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$$

$$I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_O N_O)$$

I_{CC} = Quiescent Current

ΔI_{CC} = Power Supply Current for a TTL High Input ($V_{IN} = 3.4V$)

D_H = Duty Cycle for TTL Inputs High

N_T = Number of TTL Inputs at D_H

I_{CCD} = Dynamic Current caused by an Input Transition Pair (HLH or LHL)

f_O = Output Frequency

N_O = Number of Outputs at f_O

All currents are in millamps and all frequencies are in megahertz.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

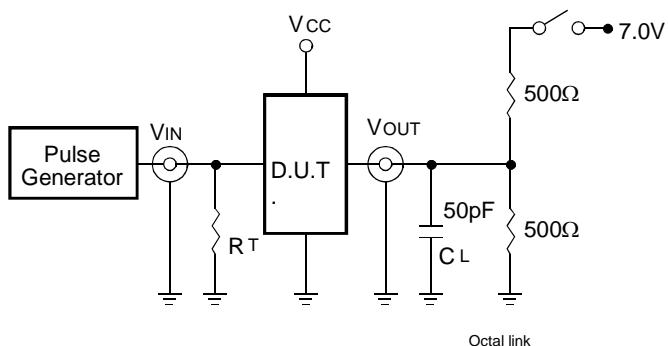
Symbol	Parameter	Condition ⁽¹⁾	74FCT2257AT		74FCT2257CT		Unit
			Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	
t_{PLH}	Propagation Delay Ix to Zx	$C_L = 50\text{pF}$ $R_L = 500\Omega$	1.5	5	1.5	4.3	ns
			1.5	7	1.5	5.2	ns
	Propagation Delay S to Zx		1.5	7	1.5	6	ns
t_{PZH}	Output Enable Time		1.5	5.5	1.5	5	ns
			1.5	5.5	1.5	5	ns

NOTES:

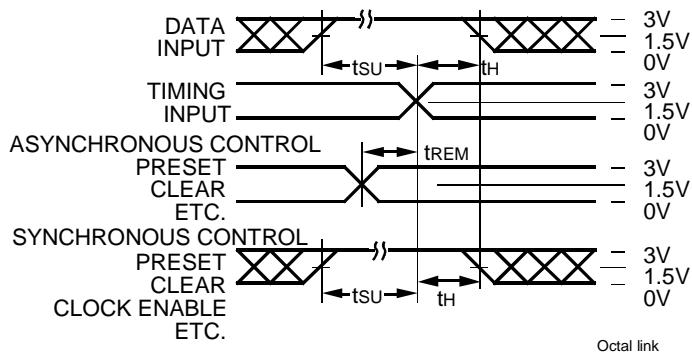
1. See test circuit and waveforms.

2. Minimum limits are guaranteed but not tested on Propagation Delays.

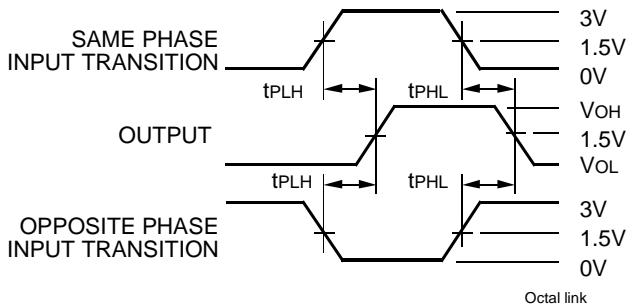
TEST CIRCUITS AND WAVEFORMS



Test Circuits for All Outputs



Set-Up, Hold, and Release Times



Propagation Delay

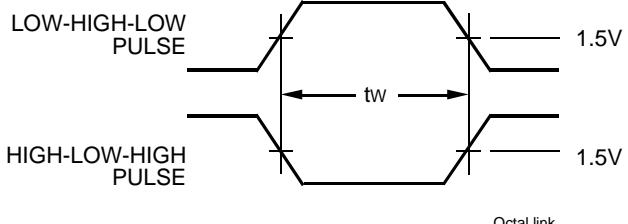
SWITCH POSITION

Test	Switch
Open Drain	Closed
Disable Low	
Enable Low	
All Other Tests	Open

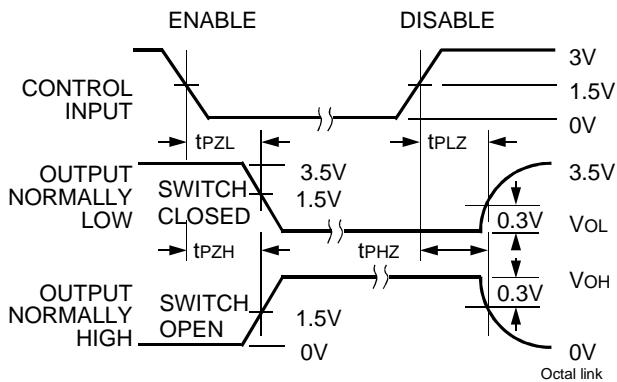
DEFINITIONS:

CL = Load capacitance: includes jig and probe capacitance.

RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.



Pulse Width

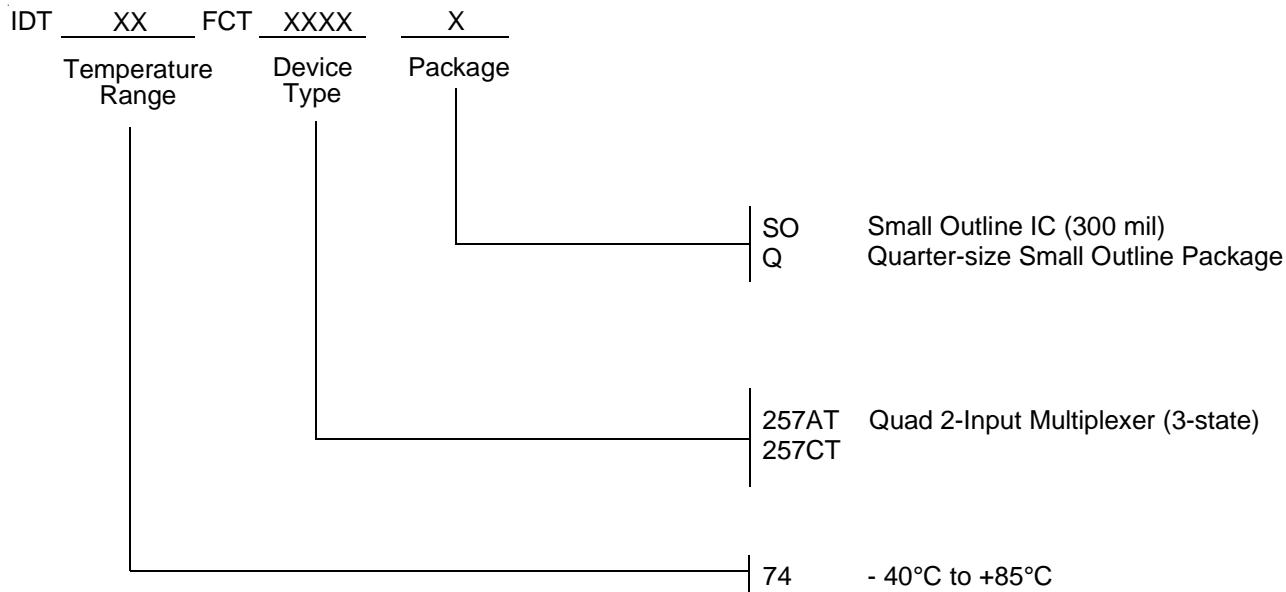


Enable and Disable Times

NOTES:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.
2. Pulse Generator for All Pulses: Rate \leq 1.0MHz; $t_f \leq 2.5\text{ns}$; $t_r \leq 2.5\text{ns}$.

ORDERING INFORMATION



DATA SHEET DOCUMENT HISTORY

6/24/2002 Updated as per PDNs Logic-00-07 and Logic-01-04



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